



Mechanical date: $A_x=A_y=210\mu\text{m}$
 $B_x=B_y=85\mu\text{m}$

Schematic and pinning diagram

Chip thickness: $635 \pm 20\mu\text{m}$

Scribe Line width - $40\mu\text{m}$.

Top Metal: Al – for wire bonding, $d=2.2\pm 0.2\mu\text{m}$

Back side : without metallization

Top Side - pin 1, **Back Side** - pin 2.

Probing: sampling testing: no bad dice inking, guaranteed good dice quantity $\geq 95\%$.

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Reverse Stand-off voltage	V_{RWM}	-	5	V
Peak Pulse Power	P_{PP}	$t_p=8/20\mu\text{s}$	35*	W
Peak Pulse Current	I_{PP}	$t_p=8/20\mu\text{s}$	2*	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	+/-8 (Contact); +/-15 (Air).	kV
Max.junction temperature	T_j	-	+150	$^{\circ}\text{C}$

Characteristics ($T_a=25^{\circ}\text{C}$)

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_R	Diode reverse leakage current.	$V=\pm 5,0\text{ V}$	-	-	90	nA
V_{BR}	Breakdown voltage. Pin 1 to 2 or Pin2 to 1.	$I_R=1\text{mA}$	5,6	-	9,4	V
C_j	Diode capacitance .	$F=1\text{MHz}$, $V_{dc}=0\text{ V}$.	-	3,0	3,5	pF
V_{CL}	lamping voltage	$I_{pp}=1,0\text{A}$; $I_{pp}= 2,0\text{A}$; $t_p= 8/20\mu\text{S}$.	-	-	10,0* 13,0*	V

*- For Device testing